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**Digital Transistor** 

Package SOT-23 (SST3)

## 1. TEST RESULT

TEST DESCRIPTION		TEST CONDITION	STANDARD	n [pcs]	Pn [pcs]
Soldering Heat Resistance	(1)	260 $\pm$ 5°C , 10sec. , Reflow Soldering , 2 times		22	0
	(2)	260±5℃ , 10sec. , Solder-Bath	JESD22-A111	22	0
	(3)	350±10°C , 3sec. , Hand Soldering		22	0
Solderability	(1)	245±5°C , 3sec. , Reflow Soldering	J-STD-002	22	0
	(2)	245±5°C , 3sec. , Solder-Bath	JESD22-B102	22	0
Thermal Shock		0°C ~ 100°C , 100cycles	-	22	0
Temperature Cycle		-55±5°C←→150±5°C , 200cycles	JESD22-A104	22	0
High Temp. High Humidity Reverse Bias		85±2°C, 85±5%RH, Specified Bias ,1000hours	JESD22-A101	22	0
Pressure Cooker Test		121±2°C , 100%RH , 203kPa , 100hours	JESD22-A102	22	0
Load Life		25℃,Pd=Pd max.,1000hours	-	22	0
High Temperature Reverse Bias		Ta=Tstg max. , Specified Bias , 1000hours	JESD22-A108	22	0
High Temperature Storage		Tstg max. , 1000hours	-	22	0
Low Temperature Storage		Tstg min. , 1000hours	-	22	0
Lead strength (lead pull)		Sample body fixed, pulling lead axis direction, 2.5N , 10±1sec.	JEITA ED-4701/400 Test Method 401	22	0

## 2. CRITERIA

ITEM CONDITION		CRITERIA		
Output current : Io(off)	Per specification	Within two times of the standard value.		
DC current gain : GI	Per specification	Within two times of the standard value.		
Physical	Visual check	No outstanding change in physical.		
Soldorobility		Reflow Soldering	Immersed surface, other than the end of pin as cut-surface, must be covered by solder.	
Solderability	Visual check	Solder-Bath	More than 95% of the electrode must be covered with solder.	

## 3. JUDGEMENT

No failure is observed from each test item.

## 4. TEST DESCRIPTION

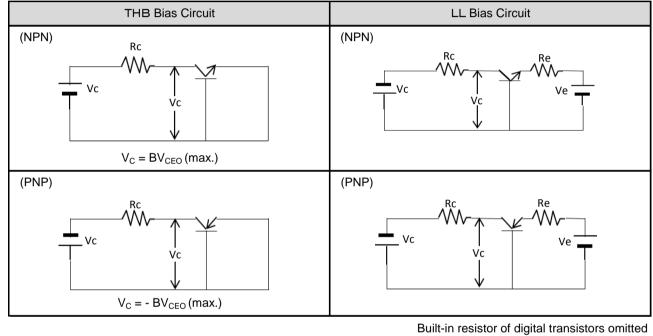
TEST DESCRIPTI			
TEST DESCRIPTI		TEST CONDITION	CRITERIA
1. Soldering Heat Resistance *4	(1)	<ol> <li>Reflow Soldering, 260±5°C(peak), 10 sec., 2 times</li> <li>After reflow soldering, leave at room temp. for more than 2h.</li> </ol>	<ul> <li>Shall be no mechanical damage.</li> <li>See (*1) for criteria on electrical characteristics.</li> </ul>
	(2) *3	<ol> <li>Dip the whole body once into solder bath. 260±5°C, 10±1sec Solder : Sn-3Ag-0.5Cu (Lead free)</li> <li>After dipping, leave at room temp. for more than 2h.</li> </ol>	<ul> <li>Shall be no mechanical damage.</li> <li>See (*1) for criteria on electrical characteristics.</li> </ul>
	(3)	<ol> <li>Hand Soldering, 350±10°C , 3sec.</li> <li>After testing, leave at room temp. for more than 2h.</li> </ol>	<ul> <li>Shall be no mechanical damage.</li> <li>See (*1) for criteria on electrical characteristics.</li> </ul>
2. Solderability *5	(1)	1) Reflow Soldering, 245±5℃(peak) , 3sec. Solder : Sn-3Ag-0.5Cu (Lead free)	<ul> <li>Immersed surface, other than the end of pin as cut-surface, must be covered by solder.</li> </ul>
	(2) *3	While body to be immersed, for 10 sec., then into solder bath of 245±5°C. Thereafter leave for natural dry at room temp. then wash off flux in 2-propanol. Solder : Sn-3Ag-0.5Cu (lead free) Flux : 2-propanol (IPA) (rosin 25wt%)	At least 95% of immersed surface, other than the end of pin as cut-surface, of must be covered by solder, which is observed through $10 \sim 20X$ magnifying glass.
3. Thermal Shock *6		<ol> <li>Temp. &amp; Time (Change within 10 sec,)</li> <li>95~100°C (Liquid), 5min ←→ 0~5°C (Liquid), 5min</li> <li>Preq. 100cycles. After completion of test,</li> <li>leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
4. Temperature Cycle *6		<ol> <li>Temp. &amp; Time (Change within 5 sec.)</li> <li>55°C (air), 30min ←→ 150°C (air), 30min</li> <li>Preq. 200cycles. After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
5. High Temp. High Humidity Reverse Bias *6		<ol> <li>Ta=85±3°C, RH=75~90%, Time : 1000h</li> <li>See (*2) for the THB bias.</li> <li>After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
6. Pressure Cooker Test *6		<ol> <li>Ta=121°C, 100%RH, P=203KPa [2atm]</li> <li>Time : 100h</li> <li>After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
7. Load Life *6		<ol> <li>Ta=25±5°C, Pd/Pd(max), Time : 1000h</li> <li>See (*2) for the THB bias.</li> <li>After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
8. High Temperature Reverse Bias *6		<ol> <li>Ta=Tstg(max)±2°C, Time : 1000h</li> <li>See (*2) for the THB bias.</li> <li>After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
9. High Temperature Storage		<ol> <li>Ta=Tstg(max), Time : 1000h</li> <li>After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
10. Low Temperature Storage		<ol> <li>Ta=Tstg(min), Time : 1000h</li> <li>After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
11. Lead Strength (Lead Pull)		The sample body is fixed, and keep pulling the lead in lead axis direction with specified load for 10±1s.	Shall be no mechanical damage, detachment, extention between the lead and the package body.

## \* REMARK

\*1 Criteria for electrical characteristics.

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• Io(off) >Standard ×2		
$\cdot \frac{\Delta GI}{GI} > \pm 20\%$		

#### \*2 Bias Circuit



\*3 Method of test 1, test 2



Immersed in solder bath

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Wash off flux in 2-propanol

\*4 Preconditioning : The test is carried out after it is left under the high temperature and the high humidity.(85°C,85%,168h)

Left to stand more than 2h under room temp.

- \*5 Preconditioning : Aging is done with the PCT device. (105°C,100%,1.22×10<sup>5</sup>Pa,4h)
- \*6 Preconditioning : Soldering heat resistance(260°C,10s) is carried out. (Reflow Soldering)

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